# E·XFL



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#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

### Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	36864
Number of I/O	68
Number of Gates	250000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/m1a3p250-vq100i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



## 1 – ProASIC3 Device Family Overview

## **General Description**

ProASIC3, the third-generation family of Microsemi flash FPGAs, offers performance, density, and features beyond those of the ProASIC<sup>PLUS®</sup> family. Nonvolatile flash technology gives ProASIC3 devices the advantage of being a secure, low power, single-chip solution that is Instant On. ProASIC3 is reprogrammable and offers time-to-market benefits at an ASIC-level unit cost. These features enable designers to create high-density systems using existing ASIC or FPGA design flows and tools.

ProASIC3 devices offer 1 kbit of on-chip, reprogrammable, nonvolatile FlashROM storage as well as clock conditioning circuitry based on an integrated phase-locked loop (PLL). The A3P015 and A3P030 devices have no PLL or RAM support. ProASIC3 devices have up to 1 million system gates, supported with up to 144 kbits of true dual-port SRAM and up to 300 user I/Os.

ProASIC3 devices support the ARM Cortex-M1 processor. The ARM-enabled devices have Microsemi ordering numbers that begin with M1A3P (Cortex-M1) and do not support AES decryption.

## **Flash Advantages**

### Reduced Cost of Ownership

Advantages to the designer extend beyond low unit cost, performance, and ease of use. Unlike SRAMbased FPGAs, flash-based ProASIC3 devices allow all functionality to be Instant On; no external boot PROM is required. On-board security mechanisms prevent access to all the programming information and enable secure remote updates of the FPGA logic. Designers can perform secure remote in-system reprogramming to support future design iterations and field upgrades with confidence that valuable intellectual property (IP) cannot be compromised or copied. Secure ISP can be performed using the industry-standard AES algorithm. The ProASIC3 family device architecture mitigates the need for ASIC migration at higher user volumes. This makes the ProASIC3 family a cost-effective ASIC replacement solution, especially for applications in the consumer, networking/ communications, computing, and avionics markets.

### Security

The nonvolatile, flash-based ProASIC3 devices do not require a boot PROM, so there is no vulnerable external bitstream that can be easily copied. ProASIC3 devices incorporate FlashLock, which provides a unique combination of reprogrammability and design security without external overhead, advantages that only an FPGA with nonvolatile flash programming can offer.

ProASIC3 devices utilize a 128-bit flash-based lock and a separate AES key to provide the highest level of protection in the FPGA industry for intellectual property and configuration data. In addition, all FlashROM data in ProASIC3 devices can be encrypted prior to loading, using the industry-leading AES-128 (FIPS192) bit block cipher encryption standard. The AES standard was adopted by the National Institute of Standards and Technology (NIST) in 2000 and replaces the 1977 DES standard. ProASIC3 devices have a built-in AES decryption engine and a flash-based AES key that make them the most comprehensive programmable logic device security solution available today. ProASIC3 devices with AES-based security provide a high level of protection for remote field updates over public networks such as the Internet, and are designed to ensure that valuable IP remains out of the hands of system overbuilders, system cloners, and IP thieves.

ARM-enabled ProASIC3 devices do not support user-controlled AES security mechanisms. Since the ARM core must be protected at all times, AES encryption is always on for the core logic, so bitstreams are always encrypted. There is no user access to encryption for the FlashROM programming data.

Security, built into the FPGA fabric, is an inherent component of the ProASIC3 family. The flash cells are located beneath seven metal layers, and many device design and layout techniques have been used to make invasive attacks extremely difficult. The ProASIC3 family, with FlashLock and AES security, is unique in being highly resistant to both invasive and noninvasive attacks.





Figure 1-2 • ProASIC3 Device Architecture Overview with Four I/O Banks (A3P250, A3P600, and A3P1000)

The FPGA core consists of a sea of VersaTiles. Each VersaTile can be configured as a three-input logic function, a D-flip-flop (with or without enable), or a latch by programming the appropriate flash switch interconnections. The versatility of the ProASIC3 core tile as either a three-input lookup table (LUT) equivalent or as a D-flip-flop/latch with enable allows for efficient use of the FPGA fabric. The VersaTile capability is unique to the Microsemi ProASIC family of third-generation architecture flash FPGAs. VersaTiles are connected with any of the four levels of routing hierarchy. Flash switches are distributed throughout the device to provide nonvolatile, reconfigurable interconnect programming. Maximum core utilization is possible for virtually any design.

### VersaTiles

The ProASIC3 core consists of VersaTiles, which have been enhanced beyond the ProASIC<sup>PLUS®</sup> core tiles. The ProASIC3 VersaTile supports the following:

- All 3-input logic functions—LUT-3 equivalent
- Latch with clear or set
- D-flip-flop with clear or set
- Enable D-flip-flop with clear or set

Refer to Figure 1-3 for VersaTile configurations.







0-I/O is set to drive out logic Low

Last Known State – I/O is set to the last value that was driven out prior to entering the programming mode, and then held at that value during programming

Z -Tristate: I/O is tristated

rom file Save to file			Show BSR De
Port Name	Macro Cell	Pin Number	1/O State (Output Only)
BIST	ADLIB:INBUF	T2	1
BYPASS_IO	ADLIB:INBUF	K1	1
CLK	ADLIB:INBUF	B1	1
ENOUT	ADLIB:INBUF	J16	1
LED	ADLIB:OUTBUF	M3	0
MONITOR(0)	ADLIB:OUTBUF	B5	0
MONITOR[1]	ADLIB:OUTBUF	C7	Z
MONITOR[2]	ADLIB:OUTBUF	D9	Z
MONITOR(3)	ADLIB:OUTBUF	D7	Z
MONITOR[4]	ADLIB:OUTBUF	A11	Z
OEa	ADLIB:INBUF	E4	Z
ОЕЬ	ADLIB:INBUF	F1	Z
OSC_EN	ADLIB:INBUF	K3	Z
PAD[10]	ADLIB:BIBUF_LVCMOS33U	M8	Z
PAD[11]	ADLIB:BIBUF_LVCMOS33D	R7	Z
PAD[12]	ADLIB:BIBUF_LVCMOS33U	D11	Z
PAD[13]	ADLIB:BIBUF_LVCMOS33D	C12	Z
PAD[14]	ADLIB:BIBUF_LVCMOS33U	R6	Z
1			-

### Figure 1-4 • I/O States During Programming Window

- 6. Click OK to return to the FlashPoint Programming File Generator window.
- Note: I/O States During programming are saved to the ADB and resulting programming files after completing programming file generation.



	Definition	Device Specific Static Power (mW)							
Parameter		A3P1000	A3P600	A3P400	A3P250	A3P125	A3P060	A3P030	A3P015
PDC1	Array static power in Active mode	See Table 2-7 on page 2-7.							
PDC2	I/O input pin static power (standard-dependent)	See Table 2-8 on page 2-7 through Table 2-10 on page 2-8.							
PDC3	I/O output pin static power (standard-dependent)	See Table 2-11 on page 2-9 through Table 2-13 on page 2-10.							
PDC4	Static PLL contribution	2.55 mW							
PDC5	Bank quiescent power (VCCI-dependent)	See Table 2-7 on page 2-7.							

### Table 2-15 • Different Components Contributing to the Static Power Consumption in ProASIC3 Devices

*Note:* \*For a different output load, drive strength, or slew rate, Microsemi recommends using the Microsemi Power spreadsheet calculator or SmartPower tool in Libero SoC software.

## **Power Calculation Methodology**

This section describes a simplified method to estimate power consumption of an application. For more accurate and detailed power estimations, use the SmartPower tool in Libero SoC software.

The power calculation methodology described below uses the following variables:

- The number of PLLs as well as the number and the frequency of each output clock generated
- · The number of combinatorial and sequential cells used in the design
- · The internal clock frequencies
- The number and the standard of I/O pins used in the design
- · The number of RAM blocks used in the design
- Toggle rates of I/O pins as well as VersaTiles—guidelines are provided in Table 2-16 on page 2-14.
- Enable rates of output buffers—guidelines are provided for typical applications in Table 2-17 on page 2-14.
- Read rate and write rate to the memory—guidelines are provided for typical applications in Table 2-17 on page 2-14. The calculation should be repeated for each clock domain defined in the design.

### Methodology

### Total Power Consumption—PTOTAL

 $P_{TOTAL} = P_{STAT} + P_{DYN}$ 

P<sub>STAT</sub> is the total static power consumption.

P<sub>DYN</sub> is the total dynamic power consumption.

### Total Static Power Consumption—P<sub>STAT</sub>

 $P_{STAT} = P_{DC1} + N_{INPUTS} + P_{DC2} + N_{OUTPUTS} + P_{DC3}$ 

N<sub>INPUTS</sub> is the number of I/O input buffers used in the design.

N<sub>OUTPUTS</sub> is the number of I/O output buffers used in the design.

### Total Dynamic Power Consumption—P<sub>DYN</sub>

P<sub>DYN</sub> = P<sub>CLOCK</sub> + P<sub>S-CELL</sub> + P<sub>C-CELL</sub> + P<sub>NET</sub> + P<sub>INPUTS</sub> + P<sub>OUTPUTS</sub> + P<sub>MEMORY</sub> + P<sub>PLL</sub>

### Global Clock Contribution—P<sub>CLOCK</sub>

 $P_{CLOCK} = (P_{AC1} + N_{SPINE}*P_{AC2} + N_{ROW}*P_{AC3} + N_{S-CELL}*P_{AC4})*F_{CLK}$ 

N<sub>SPINE</sub> is the number of global spines used in the user design—guidelines are provided in the "Spine Architecture" section of the Global Resources chapter in the *ProASIC3 FPGA Fabric User's Guide*.

N<sub>ROW</sub> is the number of VersaTile rows used in the design—guidelines are provided in the "Spine Architecture" section of the Global Resources chapter in the *ProASIC3 FPGA Fabric User's Guide*.



### Table 2-24 • Summary of I/O Timing Characteristics—Software Default Settings

#### -2 Speed Grade, Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst Case VCC = 1.425 V, Worst-Case VCCI (per standard) 1

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I/O Standard	Drive Strength	Equiv. Software Default Drive Strength Option <sup>1</sup>	Slew Rate	Capacitive Load (pF)	External Resistor ( $\Omega$ )	t <sub>bour</sub> (ns)	t <sub>DP</sub> (ns)	t <sub>DIN</sub> (ns)	t <sub>PY</sub> (ns)	t <sub>Eout</sub> (ns)	t <sub>ZL</sub> (ns)	t <sub>ZH</sub> (ns)	t <sub>LZ</sub> (ns)	t <sub>HZ</sub> (ns)	t <sub>ZLS</sub> (ns)	t <sub>ZHS</sub> (ns)	Units
3.3 V LVTTL / 3.3 V LVCMOS	12 mA	12 mA	High	35	-	0.45	2.64	0.03	0.76	0.32	2.69	2.11	2.40	2.68	4.36	3.78	ns
3.3 V LVCMOS Wide Range <sup>2</sup>	100 µA	12 mA	High	35	-	0.45	4.08	0.03	0.76	0.32	4.08	3.20	3.71	4.14	6.61	5.74	ns
2.5 V LVCMOS	12 mA	12 mA	High	35	-	0.45	2.66	0.03	0.98	0.32	2.71	2.56	2.47	2.57	4.38	4.23	ns
1.8 V LVCMOS	12 mA	12 mA	High	35	-	0.45	2.64	0.03	0.91	0.32	2.69	2.27	2.76	3.05	4.36	3.94	ns
1.5 V LVCMOS	12 mA	12 mA	High	35	-	0.45	3.05	0.03	1.07	0.32	3.10	2.67	2.95	3.14	4.77	4.34	ns
3.3 V PCI	Per PCI spec	-	High	10	25 <sup>4</sup>	0.45	2.00	0.03	0.65	0.32	2.04	1.46	2.40	2.68	3.71	3.13	ns
3.3 V PCI-X	Per PCI-X spec	-	High	10	25 <sup>4</sup>	0.45	2.00	0.03	0.62	0.32	2.04	1.46	2.40	2.68	3.71	3.13	ns
LVDS	24 mA	_	High	-	-	0.45	1.37	0.03	1.20	_	_	_	_	-	_	-	ns
LVPECL	24 mA	-	High	-	-	0.45	1.34	0.03	1.05	_	_	_	_	_	_	-	ns

Notes:

1. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ±100 µA. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.

2. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.

3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

4. Resistance is used to measure I/O propagation delays as defined in PCI specifications. See Figure 2-11 on page 2-64 for connectivity. This resistor is not required during normal operation.



### Table 2-30 • I/O Output Buffer Maximum Resistances<sup>1</sup> Applicable to Standard I/O Banks

Standard	Drive Strength	R <sub>PULL-DOWN</sub> (Ω) <sup>2</sup>	R <sub>PULL-UP</sub> (Ω) <sup>3</sup>
3.3 V LVTTL / 3.3 V LVCMOS	2 mA	100	300
	4 mA	100	300
	6 mA	50	150
	8 mA	50	150
3.3 V LVCMOS Wide Range <sup>4</sup>	100 µA	Same as regular 3.3 V LVCMOS	Same as regular 3.3 V LVCMOS
2.5 V LVCMOS	2 mA	100	200
	4 mA	100	200
	6 mA	50	100
	8 mA	50	100
1.8 V LVCMOS	2 mA	200	225
	4 mA	100	112
1.5 V LVCMOS	2 mA	200	224

Notes:

1. These maximum values are provided for informational reasons only. Minimum output buffer resistance values depend on VCCI, drive strength selection, temperature, and process. For board design considerations and detailed output buffer resistances, use the corresponding IBIS models located at http://www.microsemi.com/soc/download/ibis/default.aspx.

2. R<sub>(PULL-DOWN-MAX)</sub> = (VOLspec) / IOLspec

3. R<sub>(PULL-UP-MAX)</sub> = (VCCImax – VOHspec) / IOHspec

4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD-8B specification.

### Table 2-31 • I/O Weak Pull-Up/Pull-Down Resistances Minimum and Maximum Weak Pull-Up/Pull-Down Resistance Values

	R <sub>(WEAK</sub>	PULL-UP) <sup>1</sup> Ω)	R <sub>(WEAK P</sub> (	ull-down) <sup>2</sup> Ω)
VCCI	Min	Мах	Min	Мах
3.3 V	10 k	45 k	10 k	45 k
3.3 V (wide range I/Os)	10 k	45 k	10 k	45 k
2.5 V	11 k	55 k	12 k	74 k
1.8 V	18 k	70 k	17 k	110 k
1.5 V	19 k	90 k	19 k	140 k

Notes:

R<sub>(WEAK PULL-UP-MAX)</sub> = (VCCI<sub>MAX</sub> - VOH<sub>spec</sub>) / I<sub>(WEAK PULL-UP-MIN)</sub>
 R<sub>(WEAK PULL-DOWN-MAX)</sub> = (VOL<sub>spec</sub>) / I<sub>(WEAK PULL-DOWN-MIN)</sub>



### Table 2-51 • 3.3 V LVTTL / 3.3 V LVCMOS Low Slew

Commercial-Case Conditions:  $T_J$  = 70°C, Worst-Case VCC = 1.425 V, Worst-Case VCCI = 3.0 V Applicable to Advanced I/O Banks

Drive Strength	Equiv. Software Default Drive Strength Option <sup>1</sup>	Speed Grade	t <sub>DOUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>PY</sub>	t <sub>EOUT</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	t <sub>ZLS</sub>	t <sub>zHS</sub>	Units
100 µA	2 mA	Std.	0.60	15.86	0.04	1.54	0.43	15.86	13.51	4.09	3.80	19.25	16.90	ns
		-1	0.51	13.49	0.04	1.31	0.36	13.49	11.49	3.48	3.23	16.38	14.38	ns
		-2	0.45	11.84	0.03	1.15	0.32	11.84	10.09	3.05	2.84	14.38	12.62	ns
100 µA	4 mA	Std.	0.60	11.25	0.04	1.54	0.43	11.25	9.54	4.61	4.70	14.64	12.93	ns
		-1	0.51	9.57	0.04	1.31	0.36	9.57	8.11	3.92	4.00	12.46	11.00	ns
		-2	0.45	8.40	0.03	1.15	0.32	8.40	7.12	3.44	3.51	10.93	9.66	ns
100 µA	6 mA	Std.	0.60	11.25	0.04	1.54	0.43	11.25	9.54	4.61	4.70	14.64	12.93	ns
		-1	0.51	9.57	0.04	1.31	0.36	9.57	8.11	3.92	4.00	12.46	11.00	ns
		-2	0.45	8.40	0.03	1.15	0.32	8.40	7.12	3.44	3.51	10.93	9.66	ns
100 µA	8 mA	Std.	0.60	8.63	0.04	1.54	0.43	8.63	7.39	4.96	5.28	12.02	10.79	ns
		-1	0.51	7.34	0.04	1.31	0.36	7.34	6.29	4.22	4.49	10.23	9.18	ns
		-2	0.45	6.44	0.03	1.15	0.32	6.44	5.52	3.70	3.94	8.98	8.06	ns
100 µA	16 mA	Std.	0.60	8.05	0.04	1.54	0.43	8.05	6.93	5.03	5.43	11.44	10.32	ns
		-1	0.51	6.85	0.04	1.31	0.36	6.85	5.90	4.28	4.62	9.74	8.78	ns
		-2	0.45	6.01	0.03	1.15	0.32	6.01	5.18	3.76	4.06	8.55	7.71	ns
100 µA	24 mA	Std.	0.60	7.50	0.04	1.54	0.43	7.50	6.90	5.13	6.00	10.89	10.29	ns
		-1	0.51	6.38	0.04	1.31	0.36	6.38	5.87	4.36	5.11	9.27	8.76	ns
		-2	0.45	5.60	0.03	1.15	0.32	5.60	5.15	3.83	4.48	8.13	7.69	ns

Notes:

 The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ±100 μA. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.

2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.



## Table 2-68 • Minimum and Maximum DC Input and Output Levels Applicable to Standard I/O Banks

1.8 V LVCMOS		VIL	VIH		VOL	VOH	IOL	юн	IOSL	IOSH	IIL <sup>1</sup>	IIH <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
2 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI – 0.45	2	2	9	11	10	10
4 mA	-0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI – 0.45	4	4	17	22	10	10

Notes:

1. IIL is the input leakage current per I/O pin over recommended operation conditions where –0.3 V < VIN < VIL.

- 2. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.
- 3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
- 4. Currents are measured at 85°C junction temperature.
- 5. Software default selection highlighted in gray.



### Figure 2-9 • AC Loading

### Table 2-69 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	C <sub>LOAD</sub> (pF)
0	1.8	0.9	35

Note: \*Measuring point = Vtrip\_See Table 2-22 on page 2-22 for a complete table of trip points.



## **Output DDR Module**



### Figure 2-22 • Output DDR Timing Model

### Table 2-103 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
t <sub>DDROCLKQ</sub>	Clock-to-Out	B, E
t <sub>DDROCLR2Q</sub>	Asynchronous Clear-to-Out	C, E
t <sub>DDROREMCLR</sub>	Clear Removal	С, В
t <sub>DDRORECCLR</sub>	Clear Recovery	С, В
t <sub>DDROSUD1</sub>	Data Setup Data_F	А, В
t <sub>DDROSUD2</sub>	Data Setup Data_R	D, B
t <sub>DDROHD1</sub>	Data Hold Data_F	А, В
t <sub>DDROHD2</sub>	Data Hold Data_R	D, B



### Timing Characteristics

### Table 2-116 • RAM4K9

Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V

Parameter	Description	-2	-1	Std.	Units
t <sub>AS</sub>	Address setup time	0.25	0.28	0.33	ns
t <sub>AH</sub>	Address hold time	0.00	0.00	0.00	ns
t <sub>ENS</sub>	REN, WEN setup time	0.14	0.16	0.19	ns
t <sub>ENH</sub>	REN, WEN hold time	0.10	0.11	0.13	ns
t <sub>BKS</sub>	BLK setup time	0.23	0.27	0.31	ns
t <sub>BKH</sub>	BLK hold time	0.02	0.02	0.02	ns
t <sub>DS</sub>	Input data (DIN) setup time	0.18	0.21	0.25	ns
t <sub>DH</sub>	Input data (DIN) hold time	0.00	0.00	0.00	ns
t <sub>CKQ1</sub>	Clock High to new data valid on DOUT (output retained, WMODE = 0)	2.36	2.68	3.15	ns
	Clock High to new data valid on DOUT (flow-through, WMODE = 1)	1.79	2.03	2.39	ns
t <sub>CKQ2</sub>	Clock High to new data valid on DOUT (pipelined)	0.89	1.02	1.20	ns
t <sub>C2CWWL</sub> 1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Closing Edge	0.33	0.28	0.25	ns
t <sub>C2CWWH</sub> 1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Rising Edge	0.30	0.26	0.23	ns
t <sub>C2CRWH</sub> 1	Address collision clk-to-clk delay for reliable read access after write on same address—Applicable to Opening Edge	0.45	0.38	0.34	ns
t <sub>C2CWRH</sub> 1	Address collision clk-to-clk delay for reliable write access after read on same address— Applicable to Opening Edge	0.49	0.42	0.37	ns
t <sub>RSTBQ</sub>	RESET Low to data out Low on DOUT (flow-through)	0.92	1.05	1.23	ns
	RESET Low to Data Out Low on DOUT (pipelined)	0.92	1.05	1.23	ns
t <sub>REMRSTB</sub>	RESET removal	0.29	0.33	0.38	ns
t <sub>RECRSTB</sub>	RESET recovery	1.50	1.71	2.01	ns
t <sub>MPWRSTB</sub>	RESET minimum pulse width	0.21	0.24	0.29	ns
t <sub>CYC</sub>	Clock cycle time	3.23	3.68	4.32	ns
F <sub>MAX</sub>	Maximum frequency	310	272	231	MHz

Notes:

1. For more information, refer to the application note Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs.

2. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.



## **JTAG 1532 Characteristics**

JTAG timing delays do not include JTAG I/Os. To obtain complete JTAG timing, add I/O buffer delays to the corresponding standard selected; refer to the I/O timing characteristics in the "User I/O Characteristics" section on page 2-15 for more details.

### **Timing Characteristics**

### *Table 2-125* • JTAG 1532

```
Commercial-Case Conditions: T<sub>J</sub> = 70°C, Worst-Case VCC = 1.425 V
```

Parameter	Description	-2	-1	Std.	Units
t <sub>DISU</sub>	Test Data Input Setup Time	0.50	0.57	0.67	ns
t <sub>DIHD</sub>	Test Data Input Hold Time	1.00	1.13	1.33	ns
t <sub>TMSSU</sub>	Test Mode Select Setup Time	0.50	0.57	0.67	ns
t <sub>TMDHD</sub>	Test Mode Select Hold Time	1.00	1.13	1.33	ns
t <sub>TCK2Q</sub>	Clock to Q (data out)	6.00	6.80	8.00	ns
t <sub>RSTB2Q</sub>	Reset to Q (data out)	20.00	22.67	26.67	ns
F <sub>TCKMAX</sub>	TCK Maximum Frequency	25.00	22.00	19.00	MHz
t <sub>TRSTREM</sub>	ResetB Removal Time	0.00	0.00	0.00	ns
t <sub>TRSTREC</sub>	ResetB Recovery Time	0.20	0.23	0.27	ns
t <sub>TRSTMPW</sub>	ResetB Minimum Pulse	TBD	TBD	TBD	ns

Note: For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.



### VJTAG

### JTAG Supply Voltage

Low power flash devices have a separate bank for the dedicated JTAG pins. The JTAG pins can be run at any voltage from 1.5 V to 3.3 V (nominal). Isolating the JTAG power supply in a separate I/O bank gives greater flexibility in supply selection and simplifies power supply and PCB design.

If the JTAG interface is neither used nor planned for use, the VJTAG pin together with the TRST pin could be tied to GND.

It should be noted that VCC is required to be powered for JTAG operation; VJTAG alone is insufficient. If a device is in a JTAG chain of interconnected boards, the board containing the device can be powered down, provided both VJTAG and VCC to the part remain powered; otherwise, JTAG signals will not be able to transition the device, even in bypass mode.

Microsemi recommends that VPUMP and VJTAG power supplies be kept separate with independent filtering capacitors rather than supplying them from a common rail.

### VPUMP Programming Supply Voltage

ProASIC3 devices support single-voltage ISP of the configuration flash and FlashROM. For programming, VPUMP should be 3.3 V nominal. During normal device operation, VPUMP can be left floating or can be tied (pulled up) to any voltage between 0 V and the VPUMP maximum. Programming power supply voltage (VPUMP) range is listed in Table 2-2 on page 2-2.

When the VPUMP pin is tied to ground, it will shut off the charge pump circuitry, resulting in no sources of oscillation from the charge pump circuitry.

For proper programming, 0.01  $\mu$ F and 0.33  $\mu$ F capacitors (both rated at 16 V) are to be connected in parallel across VPUMP and GND, and positioned as close to the FPGA pins as possible.

Microsemi recommends that VPUMP and VJTAG power supplies be kept separate with independent filtering capacitors rather than supplying them from a common rail.

## **User Pins**

I/O

### User Input/Output

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Input and output signal levels are compatible with the I/O standard selected.

During programming, I/Os become tristated and weakly pulled up to  $V_{CCI}$ . With  $V_{CCI}$ , VMV, and  $V_{CC}$  supplies continuously powered up, when the device transitions from programming to operating mode, the I/Os are instantly configured to the desired user configuration.

Unused I/Os are configured as follows:

- Output buffer is disabled (with tristate value of high impedance)
- Input buffer is disabled (with tristate value of high impedance)
- Weak pull-up is programmed

### GL Globals

GL I/Os have access to certain clock conditioning circuitry (and the PLL) and/or have direct access to the global network (spines). Additionally, the global I/Os can be used as regular I/Os, since they have identical capabilities. Unused GL pins are configured as inputs with pull-up resistors.

See more detailed descriptions of global I/O connectivity in the "Clock Conditioning Circuits in IGLOO and ProASIC3 Devices" chapter of the *ProASIC3 FPGA Fabric User's Guide*. All inputs labeled GC/GF are direct inputs into the quadrant clocks. For example, if GAA0 is used for an input, GAA1 and GAA2 are no longer available for input to the quadrant globals. All inputs labeled GC/GF are direct inputs into the chip-level globals, and the rest are connected to the quadrant globals. The inputs to the global network are multiplexed, and only one input can be used as a global input.

Refer to the I/O Structure section of the handbook for the device you are using for an explanation of the naming of global pins.

### FF Flash\*Freeze Mode Activation Pin

Flash\*Freeze is available on IGLOO, ProASIC3L, and RT ProASIC3 devices. It is not supported on ProASIC3/E devices. The FF pin is a dedicated input pin used to enter and exit Flash\*Freeze mode. The FF pin is active-low, has the same characteristics as a single-ended I/O, and must meet the maximum rise and fall times. When Flash\*Freeze



QN132		QN132		QN132		
Pin Number	A3P030 Function	Pin Number	A3P030 Function	Pin Number	A3P030 Function	
A1	IO01RSB1	A37	IO26RSB0	B25	GND	
A2	IO81RSB1	A38	IO23RSB0	B26	NC	
A3	NC	A39	NC	B27	IO41RSB0	
A4	IO80RSB1	A40	IO22RSB0	B28	GND	
A5	GEC0/IO77RSB1	A41	IO20RSB0	B29	GDA0/IO37RSB0	
A6	NC	A42	IO18RSB0	B30	NC	
A7	GEB0/IO75RSB1	A43	VCC	B31	GND	
A8	IO73RSB1	A44	IO15RSB0	B32	IO33RSB0	
A9	NC	A45	IO12RSB0	B33	IO30RSB0	
A10	VCC	A46	IO10RSB0	B34	IO27RSB0	
A11	IO71RSB1	A47	IO09RSB0	B35	IO24RSB0	
A12	IO68RSB1	A48	IO06RSB0	B36	GND	
A13	IO63RSB1	B1	IO02RSB1	B37	IO21RSB0	
A14	IO60RSB1	B2	IO82RSB1	B38	IO19RSB0	
A15	NC	B3	GND	B39	GND	
A16	IO59RSB1	B4	IO79RSB1	B40	IO16RSB0	
A17	IO57RSB1	B5	NC	B41	IO13RSB0	
A18	VCC	B6	GND	B42	GND	
A19	IO54RSB1	B7	IO74RSB1	B43	IO08RSB0	
A20	IO52RSB1	B8	NC	B44	IO05RSB0	
A21	IO49RSB1	B9	GND	C1	IO03RSB1	
A22	IO48RSB1	B10	IO70RSB1	C2	IO00RSB1	
A23	IO47RSB1	B11	IO67RSB1	C3	NC	
A24	TDI	B12	IO64RSB1	C4	IO78RSB1	
A25	TRST	B13	IO61RSB1	C5	GEA0/IO76RSB1	
A26	IO44RSB0	B14	GND	C6	NC	
A27	NC	B15	IO58RSB1	C7	NC	
A28	IO43RSB0	B16	IO56RSB1	C8	VCCIB1	
A29	IO42RSB0	B17	GND	C9	IO69RSB1	
A30	IO40RSB0	B18	IO53RSB1	C10	IO66RSB1	
A31	IO39RSB0	B19	IO50RSB1	C11	IO65RSB1	
A32	GDC0/IO36RSB0	B20	GND	C12	IO62RSB1	
A33	NC	B21	IO46RSB1	C13	NC	
A34	VCC	B22	TMS	C14	NC	
A35	IO34RSB0	B23	TDO	C15	IO55RSB1	
A36	IO31RSB0	B24	IO45RSB0	C16	VCCIB1	
				_		



Package Pin Assignments

QN132				
Pin Number	A3P250 Function			
C17	IO74RSB2			
C18	VCCIB2			
C19	ТСК			
C20	VMV2			
C21	VPUMP			
C22	VJTAG			
C23	VCCIB1			
C24	IO53NSB1			
C25	IO51NPB1			
C26	GCA1/IO50PPB1			
C27	GCC0/IO48NDB1			
C28	VCCIB1			
C29	IO42NDB1			
C30	GNDQ			
C31	GBA1/IO40RSB0			
C32	GBB0/IO37RSB0			
C33	VCC			
C34	IO24RSB0			
C35	IO19RSB0			
C36	IO16RSB0			
C37	IO10RSB0			
C38	VCCIB0			
C39	GAB1/IO03RSB0			
C40	VMV0			
D1	GND			
D2	GND			
D3	GND			
D4	GND			

PQ208		PQ208		PQ208		
Pin Number	A3P400 Function	Pin Number	A3P400 Function	Pin Number	A3P400 Function	
1	GND	37	IO141PSB3	73	IO112RSB2	
2	GAA2/IO155UDB3	38	IO140PDB3	74	IO111RSB2	
3	IO155VDB3	39	IO140NDB3	75	IO110RSB2	
4	GAB2/IO154UDB3	40	VCCIB3	76	IO109RSB2	
5	IO154VDB3	41	GND	77	IO108RSB2	
6	GAC2/IO153UDB3	42	IO138PDB3	78	IO107RSB2	
7	IO153VDB3	43	IO138NDB3	79	IO106RSB2	
8	IO152UDB3	44	GEC1/IO137PDB3	80	IO104RSB2	
9	IO152VDB3	45	GEC0/IO137NDB3	81	GND	
10	IO151UDB3	46	GEB1/IO136PDB3	82	IO102RSB2	
11	IO151VDB3	47	GEB0/IO136NDB3	83	IO101RSB2	
12	IO150PDB3	48	GEA1/IO135PDB3	84	IO100RSB2	
13	IO150NDB3	49	GEA0/IO135NDB3	85	IO99RSB2	
14	IO149PDB3	50	VMV3	86	IO98RSB2	
15	IO149NDB3	51	GNDQ	87	IO97RSB2	
16	VCC	52	GND	88	VCC	
17	GND	53	VMV2	89	VCCIB2	
18	VCCIB3	54	NC	90	IO94RSB2	
19	IO148PDB3	55	GEA2/IO134RSB2	91	IO92RSB2	
20	IO148NDB3	56	GEB2/IO133RSB2	92	IO90RSB2	
21	GFC1/IO147PDB3	57	GEC2/IO132RSB2	93	IO88RSB2	
22	GFC0/IO147NDB3	58	IO131RSB2	94	IO86RSB2	
23	GFB1/IO146PDB3	59	IO130RSB2	95	IO84RSB2	
24	GFB0/IO146NDB3	60	IO129RSB2	96	GDC2/IO82RSB2	
25	VCOMPLF	61	IO128RSB2	97	GND	
26	GFA0/IO145NPB3	62	VCCIB2	98	GDB2/IO81RSB2	
27	VCCPLF	63	IO125RSB2	99	GDA2/IO80RSB2	
28	GFA1/IO145PPB3	64	IO123RSB2	100	GNDQ	
29	GND	65	GND	101	тск	
30	GFA2/IO144PDB3	66	IO121RSB2	102	TDI	
31	IO144NDB3	67	IO119RSB2	103	TMS	
32	GFB2/IO143PDB3	68	IO117RSB2	104	VMV2	
33	IO143NDB3	69	IO115RSB2	105	GND	
34	GFC2/IO142PDB3	70	IO113RSB2	106	VPUMP	
35	IO142NDB3	71	VCC	107	NC	
36	NC	72	VCCIB2	108	TDO	



PQ208		PQ208		PQ208		
Pin Number	A3P600 Function	Pin Number	A3P600 Function	Pin Num	ber A3P600 Function	
1	GND	37	IO152PDB3	73	IO120RSB2	
2	GAA2/IO174PDB3	38	IO152NDB3	74	IO119RSB2	
3	IO174NDB3	39	IO150PSB3	75	IO118RSB2	
4	GAB2/IO173PDB3	40	VCCIB3	76	IO117RSB2	
5	IO173NDB3	41	GND	77	IO116RSB2	
6	GAC2/IO172PDB3	42	IO147PDB3	78	IO115RSB2	
7	IO172NDB3	43	IO147NDB3	79	IO114RSB2	
8	IO171PDB3	44	GEC1/IO146PDB3	80	IO112RSB2	
9	IO171NDB3	45	GEC0/IO146NDB3	81	GND	
10	IO170PDB3	46	GEB1/IO145PDB3	82	IO111RSB2	
11	IO170NDB3	47	GEB0/IO145NDB3	83	IO110RSB2	
12	IO169PDB3	48	GEA1/IO144PDB3	84	IO109RSB2	
13	IO169NDB3	49	GEA0/IO144NDB3	85	IO108RSB2	
14	IO168PDB3	50	VMV3	86	IO107RSB2	
15	IO168NDB3	51	GNDQ	87	IO106RSB2	
16	VCC	52	GND	88	VCC	
17	GND	53	VMV2	89	VCCIB2	
18	VCCIB3	54	GEA2/IO143RSB2	90	IO104RSB2	
19	IO166PDB3	55	GEB2/IO142RSB2	91	IO102RSB2	
20	IO166NDB3	56	GEC2/IO141RSB2	92	IO100RSB2	
21	GFC1/IO164PDB3	57	IO140RSB2	93	IO98RSB2	
22	GFC0/IO164NDB3	58	IO139RSB2	94	IO96RSB2	
23	GFB1/IO163PDB3	59	IO138RSB2	95	IO92RSB2	
24	GFB0/IO163NDB3	60	IO137RSB2	96	GDC2/IO91RSB2	
25	VCOMPLF	61	IO136RSB2	97	GND	
26	GFA0/IO162NPB3	62	VCCIB2	98	GDB2/IO90RSB2	
27	VCCPLF	63	IO135RSB2	99	GDA2/IO89RSB2	
28	GFA1/IO162PPB3	64	IO133RSB2	100	GNDQ	
29	GND	65	GND	101	ТСК	
30	GFA2/IO161PDB3	66	IO131RSB2	102	TDI	
31	IO161NDB3	67	IO129RSB2	103	TMS	
32	GFB2/IO160PDB3	68	IO127RSB2	104	VMV2	
33	IO160NDB3	69	IO125RSB2	105	GND	
34	GFC2/IO159PDB3	70	IO123RSB2	106	VPUMP	
35	IO159NDB3	71	VCC	107	GNDQ	
36	VCC	72	VCCIB2	108	TDO	



FG144			
Pin Number	A3P125 Function		
K1	GEB0/IO109RSB1		
K2	GEA1/IO108RSB1		
K3	GEA0/IO107RSB1		
K4	GEA2/IO106RSB1		
K5	IO100RSB1		
K6	IO98RSB1		
K7	GND		
K8	IO73RSB1		
K9	GDC2/IO72RSB1		
K10	GND		
K11	GDA0/IO66RSB0		
K12	GDB0/IO64RSB0		
L1	GND		
L2	VMV1		
L3	GEB2/IO105RSB1		
L4	IO102RSB1		
L5	VCCIB1		
L6	IO95RSB1		
L7	IO85RSB1		
L8	IO74RSB1		
L9	TMS		
L10	VJTAG		
L11	VMV1		
L12	TRST		
M1	GNDQ		
M2	GEC2/IO104RSB1		
M3	IO103RSB1		
M4	IO101RSB1		
M5	IO97RSB1		
M6	IO94RSB1		
M7	IO86RSB1		
M8	IO75RSB1		
M9 TDI			
M10 VCCIB1			
M11	VPUMP		
M12	GNDQ		

FG256		FG256		FG256		
Pin Number	A3P1000 Function	Pin Number	A3P1000 Function	Pin Number	A3P1000 Function	
H3	GFB1/IO208PPB3	K9	GND	M15	GDC1/IO111PDB1	
H4	VCOMPLF	K10	GND	M16	IO107NDB1	
H5	GFC0/IO209NPB3	K11	VCC	N1	IO194PSB3	
H6	VCC	K12	VCCIB1	N2	IO192PPB3	
H7	GND	K13	IO95NPB1	N3	GEC1/IO190PPB3	
H8	GND	K14	IO100NPB1	N4	IO192NPB3	
H9	GND	K15	IO102NDB1	N5	GNDQ	
H10	GND	K16	IO102PDB1	N6	GEA2/IO187RSB2	
H11	VCC	L1	IO202NDB3	N7	IO161RSB2	
H12	GCC0/IO91NPB1	L2	IO202PDB3	N8	IO155RSB2	
H13	GCB1/IO92PPB1	L3	IO196PPB3	N9	IO141RSB2	
H14	GCA0/IO93NPB1	L4	IO193PPB3	N10	IO129RSB2	
H15	IO96NPB1	L5	VCCIB3	N11	IO124RSB2	
H16	GCB0/IO92NPB1	L6	GND	N12	GNDQ	
J1	GFA2/IO206PSB3	L7	VCC	N13	IO110PDB1	
J2	GFA1/IO207PDB3	L8	VCC	N14	VJTAG	
J3	VCCPLF	L9	VCC	N15	GDC0/IO111NDB1	
J4	IO205NDB3	L10	VCC	N16	GDA1/IO113PDB1	
J5	GFB2/IO205PDB3	L11	GND	P1	GEB1/IO189PDB3	
J6	VCC	L12	VCCIB1	P2	GEB0/IO189NDB3	
J7	GND	L13	GDB0/IO112NPB1	P3	VMV2	
J8	GND	L14	IO106NDB1	P4	IO179RSB2	
J9	GND	L15	IO106PDB1	P5	IO171RSB2	
J10	GND	L16	IO107PDB1	P6	IO165RSB2	
J11	VCC	M1	IO197NSB3	P7	IO159RSB2	
J12	GCB2/IO95PPB1	M2	IO196NPB3	P8	IO151RSB2	
J13	GCA1/IO93PPB1	M3	IO193NPB3	P9	IO137RSB2	
J14	GCC2/IO96PPB1	M4	GEC0/IO190NPB3	P10	IO134RSB2	
J15	IO100PPB1	M5	VMV3	P11	IO128RSB2	
J16	GCA2/IO94PSB1	M6	VCCIB2	P12	VMV1	
K1	GFC2/IO204PDB3	M7	VCCIB2	P13	TCK	
K2	IO204NDB3	M8	IO147RSB2	P14	VPUMP	
K3	IO203NDB3	M9	IO136RSB2	P15	TRST	
K4	IO203PDB3	M10	VCCIB2	P16	GDA0/IO113NDB1	
K5	VCCIB3	M11	VCCIB2	R1	GEA1/IO188PDB3	
K6	VCC	M12	VMV2	R2	GEA0/IO188NDB3	
K7	GND	M13	IO110NDB1	R3	IO184RSB2	
K8	GND	M14	GDB1/IO112PPB1	R4	GEC2/IO185RSB2	

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Package Pin Assignments

FG484		FG484		FG484		
Pin Number	A3P1000 Function	Pin Number	A3P1000 Function	Pin Number	A3P1000 Function	
A1	GND	B15	IO63RSB0	D7	GAB0/IO02RSB0	
A2	GND	B16	IO66RSB0	D8	IO16RSB0	
A3	VCCIB0	B17	IO68RSB0	D9	IO22RSB0	
A4	IO07RSB0	B18	IO70RSB0	D10	IO28RSB0	
A5	IO09RSB0	B19	NC	D11	IO35RSB0	
A6	IO13RSB0	B20	NC	D12	IO45RSB0	
A7	IO18RSB0	B21	VCCIB1	D13	IO50RSB0	
A8	IO20RSB0	B22	GND	D14	IO55RSB0	
A9	IO26RSB0	C1	VCCIB3	D15	IO61RSB0	
A10	IO32RSB0	C2	IO220PDB3	D16	GBB1/IO75RSB0	
A11	IO40RSB0	C3	NC	D17	GBA0/IO76RSB0	
A12	IO41RSB0	C4	NC	D18	GBA1/IO77RSB0	
A13	IO53RSB0	C5	GND	D19	GND	
A14	IO59RSB0	C6	IO10RSB0	D20	NC	
A15	IO64RSB0	C7	IO14RSB0	D21	NC	
A16	IO65RSB0	C8	VCC	D22	NC	
A17	IO67RSB0	C9	VCC	E1	IO219NDB3	
A18	IO69RSB0	C10	IO30RSB0	E2	NC	
A19	NC	C11	IO37RSB0	E3	GND	
A20	VCCIB0	C12	IO43RSB0	E4	GAB2/IO224PDB3	
A21	GND	C13	NC	E5	GAA2/IO225PDB3	
A22	GND	C14	VCC	E6	GNDQ	
B1	GND	C15	VCC	E7	GAB1/IO03RSB0	
B2	VCCIB3	C16	NC	E8	IO17RSB0	
B3	NC	C17	NC	E9	IO21RSB0	
B4	IO06RSB0	C18	GND	E10	IO27RSB0	
B5	IO08RSB0	C19	NC	E11	IO34RSB0	
B6	IO12RSB0	C20	NC	E12	IO44RSB0	
B7	IO15RSB0	C21	NC	E13	IO51RSB0	
B8	IO19RSB0	C22	VCCIB1	E14	IO57RSB0	
B9	IO24RSB0	D1	IO219PDB3	E15	GBC1/IO73RSB0	
B10	IO31RSB0	D2	IO220NDB3	E16	GBB0/IO74RSB0	
B11	IO39RSB0	D3	NC	E17	IO71RSB0	
B12	IO48RSB0	D4	GND	E18	GBA2/IO78PDB1	
B13	IO54RSB0	D5	GAA0/IO00RSB0	E19	IO81PDB1	
B14	IO58RSB0	D6	GAA1/IO01RSB0	E20	GND	



Datasheet Information

Revision	Changes	Page
Revision 11 (March 2012)	Note indicating that A3P015 is not recommended for new designs has been added. The "Devices Not Recommended For New Designs" section is new (SAR 36760).	I to IV
	The following sentence was removed from the Advanced Architecture section: "In addition, extensive on-chip programming circuitry allows for rapid, single- voltage (3.3 V) programming of IGLOO devices via an IEEE 1532 JTAG interface" (SAR 34687).	NA
	The reference to guidelines for global spines and VersaTile rows, given in the "Global Clock Contribution—PCLOCK" section, was corrected to the "Spine Architecture" section of the Global Resources chapter in the <i>ProASIC3 FPGA Fabric User's Guide</i> (SAR 34734).	2-12
	Figure 2-4 • Input Buffer Timing Model and Delays (Example) has been modified for the DIN waveform; the Rise and Fall time label has been changed to tDIN (35430).	2-16
	The AC Loading figures in the "Single-Ended I/O Characteristics" section were updated to match tables in the "Summary of I/O Timing Characteristics – Default I/O Software Settings" section (SAR 34883).	2-32
	Added values for minimum pulse width and removed the FRMAX row from Table 2-107 through Table 2-114 in the "Global Tree Timing Characteristics" section. Use the software to determine the FRMAX for the device you are using (SARs 37279, 29269).	2-85